

N-CHANNEL GaAs HJ-FET NE651R479A

0.4 W L-BAND POWER GaAs HJ-FET

DESCRIPTION

The NE651R479A is a 0.4 W GaAs HJ-FET designed for middle power transmitter applications for mobile communication and wireless PC LAN systems. It is capable of delivering 0.4 W of output power (CW) with high linear gain, high efficiency and excellent distortion and as a driver amplifier for our NE6510179A and NE6510379A.

Reliability and performance uniformity are assured by NEC's stringent quality and control procedures.

FEATURES

· GaAs HJ-FET structure

High output power
 Pout = +27.0 dBm TYP. @ VDs = 3.5 V, IDset = 50 mA, f = 900 MHz, Pin = +13 dBm

 $P_{\text{out}} = +27.0 \text{ dBm TYP.} \ @ \ \text{V}_{\text{DS}} = 3.5 \text{ V}, \ I_{\text{Dset}} = 50 \text{ mA}, \ f = 1.9 \text{ GHz}, \ P_{\text{in}} = +15 \text{ dBm}$

Pout = +29.5 dBm TYP. @ VDS = 5.0 V, IDset = 50 mA, f = 1.9 GHz, Pin = +15 dBm

High linear gain
 : G_L = 14.0 dB TYP. @ V_{DS} = 3.5 V, I_{Dset} = 50 mA, f = 900 MHz, P_{in} = 0 dBm

 $G_L = 12.0 \text{ dB TYP}$. @ $V_{DS} = 3.5 \text{ V}$, $I_{Dset} = 50 \text{ mA}$, f = 1.9 GHz, $P_{in} = 0 \text{ dBm}$

GL = 12.0 dB TYP. @ VDS = 5.0 V, IDSET = 50 mA, f = 1.9 GHz, PID = 0 dBm

High power added efficiency: 60 % TYP. @ VDS = 3.5 V, IDSet = 50 mA, f = 900 MHz, Pin = +13 dBm

60 % TYP. @ $V_{DS} = 3.5 \text{ V}$, $I_{Dset} = 50 \text{ mA}$, f = 1.9 GHz, $P_{in} = +15 \text{ dBm}$

58 % TYP. @ $V_{DS} = 5.0 \text{ V}$, $I_{Dset} = 50 \text{ mA}$, f = 1.9 GHz, $P_{in} = +15 \text{ dBm}$

ORDERING INFORMATION

Part Number	Package	Supplying Form
NE651R479A-T1		12 mm wide embossed taping Qty 1 kpcs/reel

Remark To order evaluation samples, contact your nearby sales office.

Part number for sample order: NE651R479A

Caution Please handle this device at static-free workstation, because this is an electrostatic sensitive device.

The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version. Not all devices/types available in every country. Please check with local NEC Compound Semiconductor Devices representative for availability and additional information.



ABSOLUTE MAXIMUM RATINGS (TA = +25 °C)

Operation in excess of any one of these parameters may result in permanent damage.

Parameter	Symbol	Ratings	Unit
Drain to Source Voltage	Vos	8	V
Gate to Source Voltage	Vgso	-4	V
Drain Current	ΙD	1.0	Α
Gate Forward Current	lgf	10	mA
Gate Reverse Current	Igr	10	mA
Total Power Dissipation	Ptot	2.5	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-65 to +150	°C

* RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Drain to Source Voltage	Vos		-	3.5	6.0	V
Gain Compression	Gcomp		-	-	3.0	dB
Channel Temperature	Tch		-	-	+125	°C

ELECTRICAL CHARACTERISTICS

(TA = +25 °C, unless otherwise specified, using NEC standard test fixture.)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Saturated Drain Current	IDSS	V _{DS} = 2.5 V, V _{GS} = 0 V	-	0.7	-	Α
Pinch-off Voltage	Vp	V _{DS} = 2.5 V, I _D = 5 mA	-2.0	-	-0.4	V
Gate to Drain Break Down Voltage	BVgd	I _{gd} = 5 mA	12	_	_	V
Thermal Resistance	Rth	Channel to Case	-	30	50	°C/W
Output Power	Pout	f = 1.9 GHz, V _{DS} = 3.5 V,	26.0	27.0	_	dBm
Drain Current	ΙD	P_{in} = +15 dBm, R_g = 1 k Ω ,	-	220	-	mA
Power Added Efficiency	η add	IDset = 50 mA (RF OFF)	52	60	-	%
Linear Gain Note 1	GL	Note 2	_	12.0	-	dB

Notes 1. $P_{in} = 0 dBm$

2. DC performance is 100 % testing. RF performance is testing several samples per wafer. Wafer rejection criteria for standard devices is 1 reject for several samples.



TYPICAL RF PERFORMANCE FOR REFERENCE (NOT SPECIFIED)

(TA = +25 °C, unless otherwise specified, using NEC standard test fixture.)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Output Power	Pout	f = 900 MHz, V _{DS} = 3.5 V,	1	27.0	ı	dBm
Drain Current	lο	P_{in} = +13 dBm, R_g = 1 k Ω ,	-	230	-	mA
Power Added Efficiency	η add	I _{Dset} = 50 mA (RF OFF)	-	60	-	%
Linear Gain Note	G∟		-	14.0	-	dB

Note $P_{in} = 0 dBm$

TYPICAL RF PERFORMANCE FOR REFERENCE (NOT SPECIFIED)

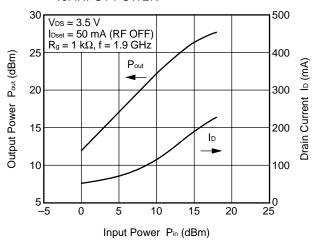
(TA = +25 °C, unless otherwise specified, using NEC standard test fixture.)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Output Power	Pout	f = 1.9 GHz, V _{DS} = 5.0 V,	-	29.5	-	dBm
Drain Current	lo	$P_{\text{in}} = +15 \text{ dBm}, \ R_g = 1 \text{ k}\Omega,$	-	350		mA
Power Added Efficiency	η add	IDset = 50 mA (RF OFF)	_	58	-	%
Linear Gain Note	G∟		=	12.0	_	dB

Note $P_{in} = 0 dBm$

TYPICAL CHARACTERISTICS (TA = +25 °C)

OUTPUT POWER, DRAIN CURRENT vs. INPUT POWER



Remark The graph indicates nominal characteristics.



S-PARAMETERS

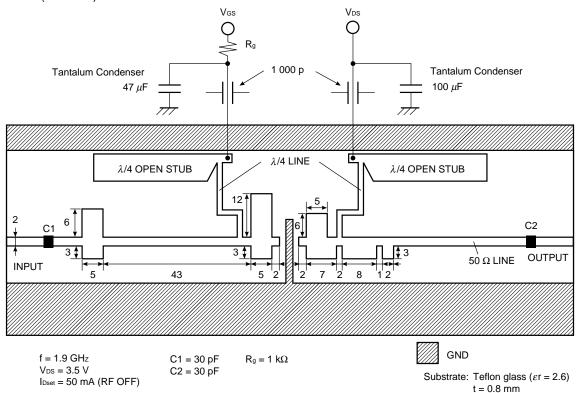
Test Conditions: VDS = 3.5 V, IDSet = 50 mA (RF OFF)

Frequency		S ₁₁		S ₂₁		S ₁₂		S ₂₂
GHz	MAG.	ANG. (deg.)						
600	0.868	-168.8	6.120	96.9	0.046	15.7	0.536	-170.3
700	0.866	-172.7	5.225	95.0	0.046	14.9	0.537	-173.9
800	0.864	-176.9	4.641	93.0	0.045	14.8	0.541	-177.1
900	0.863	-179.4	4.145	91.6	0.045	15.4	0.540	-179.6
1000	0.868	176.6	3.730	89.4	0.045	15.8	0.541	178.0
1100	0.862	173.6	3.359	88.3	0.045	16.6	0.542	175.5
1200	0.860	170.8	3.152	87.5	0.046	16.6	0.542	173.4
1300	0.861	168.3	2.894	85.8	0.047	15.7	0.535	171.9
1400	0.859	165.4	2.695	85.2	0.047	15.5	0.533	170.1
1500	0.861	162.2	2.527	84.2	0.046	16.1	0.533	167.8
1600	0.862	159.3	2.387	82.9	0.046	17.0	0.533	165.9
1700	0.857	156.7	2.261	82.8	0.047	17.1	0.532	163.8
1800	0.855	153.5	2.229	80.9	0.046	17.0	0.537	161.1
1900	0.856	150.0	2.093	77.8	0.046	16.6	0.538	158.4
2000	0.860	146.7	1.946	76.9	0.045	16.3	0.537	156.0
2100	0.860	142.9	1.884	75.5	0.045	16.9	0.533	154.0
2200	0.863	140.1	1.785	73.6	0.045	18.4	0.533	149.6



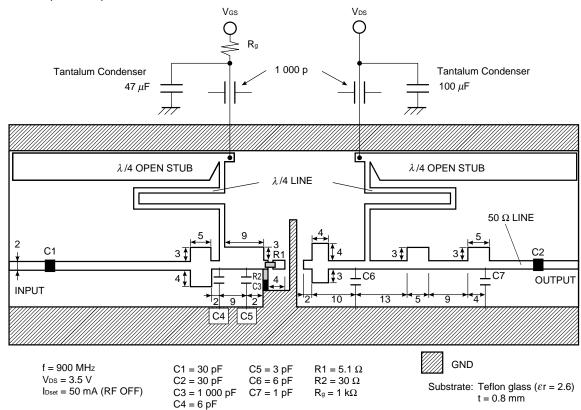
APPLICATION CIRCUIT EXAMPLE

f = 1.9 GHz (Unit: mm)



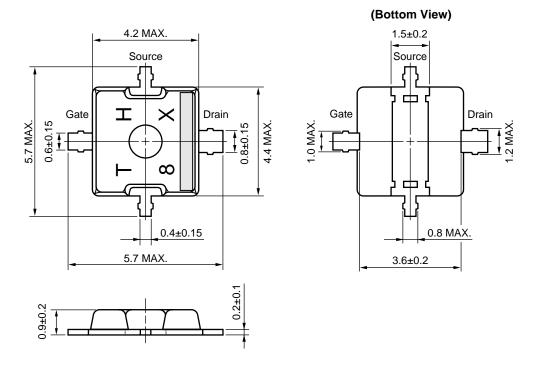
APPLICATION CIRCUIT EXAMPLE

f = 900 MHz (Unit: mm)

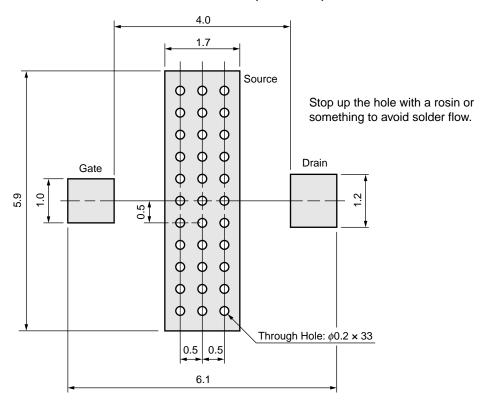


PACKAGE DIMENSIONS

79A (UNIT: mm)



79A PACKAGE RECOMMENDED P.C.B. LAYOUT (UNIT: mm)





RECOMMENDED SOLDERING CONDITIONS

This product should be soldered and mounted under the following recommended conditions. For soldering methods and conditions other than those recommended below, contact your nearby sales office.

Soldering Method	Soldering Conditions	Recommended Condition Symbol
Infrared Reflow	Package peak temperature: 235 °C or below, Time: 30 seconds or less (at 210 °C or higher), Count: 2 times or less, Exposure: limit: None Note	IR35-00-2
Partial Heating	Pin temperature: 260 °C or below, Time: 5 seconds or less (per pin row) Exposure: limit: None Note	-

Note After opening the dry pack, store it at 25 °C or less and 65 % RH or less for the allowable storage period.

Caution Do not use different soldering methods together (except for partial heating).

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SAFETY INFORMATION ON THIS PRODUCT

Caution GaAs Products	The product contains gallium arsenide, GaAs.
	GaAs vapor and powder are hazardous to human health if inhaled or ingested.
	Do not destroy or burn the product.
	Do not cut or cleave off any part of the product.
	Do not crush or chemically dissolve the product.
	Do not put the product in the mouth.
	Follow related laws and ordinances for disposal. The product should be excluded from general
	industrial waste or household garbage.

▶Business issue

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▶ Technical issue

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